

 Application/Control No.	Applicant(s)/Patent under Reexamination	
10/625,520	FUJISHIRO ET AL.	
Examiner	Art Unit	<del></del> <del>*-</del>
ANH H. DO	2624	

	SEARCHED					
Class	Subclass	Date	Examiner			
382	232, 240,	10/1/06	At)			
	244,248,					
	239, 232					
375	240.16					
	240.29					
348	416.1					
	699					
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INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
PALM	10/1/08	AD		
EAST (US)				
EAST (EPO, JPO)				
EAST (US-16-PLEB)	·			
NPL (JEST)				
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